PCN Number: 202		200312000.1				PCN Date:		e:	Mar 18, 2020		
Title:	_	fication of MI 005HV devices		3 as an ac	dditional Fa	b and Asse	embly	sit	e opti	ons for select	
Custo	omer Conta	act:	PC	N Manag	<u>er</u>	D	Dept:			Quality Services	5
Prop	osed 1 <sup>st</sup> Sh	ip Date:	Ju	n 18, 202	20	Estimate Availabil		mp		Date provided a sample request	
Chan	ge Type:										
	Assembly Si	te		Assem	bly Process	6			Asse	embly Materials	
	Design		Electrical Specification						Mechanical Specification		
	Test Site			Packin	g/Shipping	/Labeling			Test	Process	
	Wafer Bump	Site					Waf	er Bump Proces	S		
	Wafer Fab S	ite			Fab Materi				Waf	er Fab Process	
					umber chai						
					<b>PCN Det</b>	ails					
Texas		ts is pleased							as add	ditional fabricati	on
	facility for the selected devices listed in the "Product Affected" section.  Current Fab Site  Additional Fab Site										
Cur	rent Fab Site	Process		Wafe Diame	_	Iditional ab Site	P	roc	ess	Wafer Diamete	r
		Process ABCD05HV			ter F						r
M.A.	Site AINEFAB details are p	ABCD05HV	ı	Diamet 200 m	ter F	ab Site			cess	Diamete	r
Qual (	<b>Site</b> AINEFAB	ABCD05HV provided in th	ı	Diamet 200 m	ter F	ab Site			cess	Diamete	r
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Sample product shipping label (not actual product label)

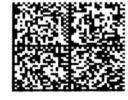
TEXAS INSTRUMENTS

MADE IN: Malaysia 2DC: 2Q:

MSL 2 /260C/1 YEAR SEAL DT MSL 1 /235C/UNLIM 03/29/04

OPT: 39

(L)T0:3750



(1P) \$N74L\$07N\$R (Q) 2000 (D) 0336 (31T) LOT: 3959047MLA (4W) TKY (1T) 7523483512 (P) (2P) REV: (V) 0033917 (20L) CSO: SHE (21L) CCO: USA (22L) ASO: MLA (23L) ACO: MYS

**Product Affected:** 

LBL:

5A

LM25117PMH/NOPB	LM25117PSQ/NOPB	LM34937PMH/NOPB	LM34937PSQX/NOPB
LM25117PMHE/NOPB	LM25117PSQE/NOPB	LM34937PMHX/NOPB	
LM25117PMHX/NOPB	LM25117PSQX/NOPB	LM34937PSQ/NOPB	

## **Qualification Report**

(As per AEC-Q100 and JEDEC Guidelines)

## Approve Date 07-January-2020

## Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	Test Name / Condition	Duration	Qual Device: LM25117QPMHX/NOPB	QBS Process Reference TCAN1042HVDRQ1
HAST	Biased HAST, 130C/85%RH	96 Hours	3/231/0	3/231/0
AC	Autoclave 121C	96 Hours	3/231/0	3/231/0
TC	Temperature Cycle, -65/150C	500 Cycles	3/231/0	3/231/0
HTSL	High Temp. Storage Bake, 150C	1000 Hours	1/45/0	1/45/0
HTOL	Life Test, 125C	1000 Hours	3/231/0	3/231/0
ELFR	Early Life Failure Rate, 150C	24 Hours	-	3/2400/0
HBM	ESD - HBM	2000 V	1/3/0	1/3/0
CDM	ESD - CDM	750 V	1/3/0	1/3/0
LU	Latch-up	(per JESD78)	1/6/0	1/6/0
ED	Electrical Distributions	Per datasheet parameters	3/90/0	3/90/0

Qual Device LM25117QPMHX/NOPB is qualified at LEVEL3-260C

A1 (PC): Preconditioning:

Performed for THB, Biased HAST, AC, uHAST, TC & PTC samples, as applicable.

Ambient Operating Temperature by Automotive Grade Level:

Grade 0 (or E): -40°C to +150°C Grade 1 (or Q): -40°C to +125°C Grade 2 (or T): -40°C to +105°C Grade 3 (or I): -40°C to +85°C

E1 (TEST): Electrical test temperatures of Qual samples (High temperature according to Grade level):

Room/Hot/Cold: HTOL, ED

Room/Hot: THB / HAST, TC / PTC, HTSL, ELFR, ESD & LU

Room: AC/uHAST

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

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